

May 2008

# FDD8447L 40V N-Channel PowerTrench<sup>®</sup> MOSFET 40V, 50A, 8.5mΩ

### **Features**

- Max  $r_{DS(on)} = 8.5 \text{m}\Omega$  at  $V_{GS} = 10 \text{V}$ ,  $I_D = 14 \text{A}$
- Max  $r_{DS(on)} = 11.0 \text{m}\Omega$  at  $V_{GS} = 4.5 \text{V}$ ,  $I_D = 11 \text{A}$
- Fast Switching
- RoHS Compliant



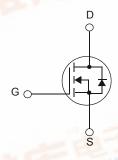
## **General Description**

This N-Channel MOSFET has been produced using Fairchild Semiconductor's proprietary PowerTrench® technology to deliver low  $r_{DS(on)}$  and optimized BV<sub>DSS</sub> capability to offer superior performance benefit in the application.

## **Applications**

- Inverter
- Power Supplies





# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	W/e		Ratings	Units
$V_{DS}$	Drain to Source Voltage	Mary .		40	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25°C		50	
- 45	-Continuous (Silicon limited)	T <sub>C</sub> = 25°C		57	^
ID	-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	15.2	A
11118	-Pulsed			100	L FAT
Is	Max Pulse Diode Current			100	Α
E <sub>AS</sub>	Drain-Source Avalanche Energy		(Note 3)	153	mJ
	Power Dissipation T <sub>C</sub> = 25°C		N THE	44	- T - T - F
$P_{D}$	T <sub>A</sub> = 25°C	41	(Note 1a)	3.1	W
	T <sub>A</sub> = 25°C	ME I	(Note 1b)	1.3	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	WILL		-55 to +150	°C

## Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case		2.8	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	40	°C/W
Rom	Thermal Resistance, Junction to Ambient	(Note 1b)	96	

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8447L	FDD8447L	D-PAK(TO-252)	13"	12mm	2500 units

# **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Parameter Test Conditions		Тур	Max	Units
Off Chara	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	40			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, referenced to 25°C		35		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 32V, V <sub>GS</sub> = 0V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{GS} = 0V$			±100	nA

## On Characteristics (Note 2)

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.0	1.9	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, referenced to 25°C		-5		mV/°C
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 14A		7.0	8.5	
r <sub>DS(on)</sub>	r <sub>DS(on)</sub> Static Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 11A$		8.5	11.0	mΩ
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 14A, T <sub>J</sub> =125°C		10.4	14.0	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5V, I <sub>D</sub> = 14A		58		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	\\ - 20\\ \\ - 0\\	1970	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 20V, V_{GS} = 0V,$ f = 1MHz	250	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 111112	150	pF
R <sub>g</sub>	Gate Resistance	f = 1MHz	1.27	Ω

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		12	21	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 20V, I_{D} = 1A$ $V_{GS} = 10V, R_{GEN} = 6\Omega$	12	21	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		38	61	ns
t <sub>f</sub>	Fall Time		9	18	ns
$Q_{g(TOT)}$	Total Gate Charge, V <sub>GS</sub> = 10V		37	52	nC
$Q_{g(TOT)}$	Total Gate Charge, V <sub>GS</sub> = 5V	V <sub>DD</sub> = 20V, I <sub>D</sub> = 14A V <sub>GS</sub> = 10V	20	28	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>GS</sub> - 10V	6		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		7		nC

### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current		(Note 1a)		2.6	Α
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 14A$	(Note 2)	0.8	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I = 14A di/dt = 100A/.	16	22		ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = 14A, di/dt = 100A/μs		11		nC

#### Notes:

4

R<sub>θ,JA</sub> is the sum of the junction-to-case and case-to- ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.

R<sub>θ,JC</sub> is guaranteed by design while R<sub>θ,JA</sub> is determined by the user's board design.

a. 40°C/W when mounted on a 1 in2 pad of 2 oz copper

b. 96°C/W when mounted on a minimum pad.

<sup>2:</sup> Pulse Test: Pulse Width <  $300\mu$ s, Duty cycle < 2.0%.

<sup>3:</sup> Starting TJ =  $25^{\circ}$ C, L = 1mH, IAS = 17.5A, VDD = 40V, VGS = 10V.

# **Typical Characteristics**

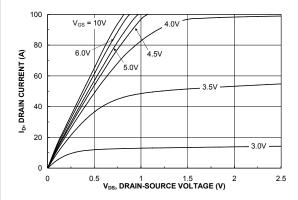


Figure 1. On-Region Characteristics

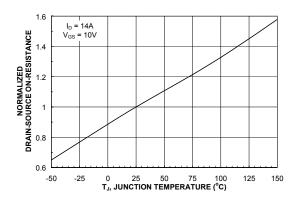


Figure 3. On-Resistance Variation with Temperature

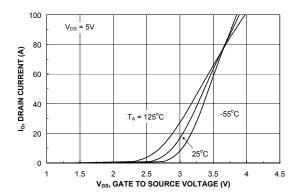


Figure 5. Transfer Characteristics

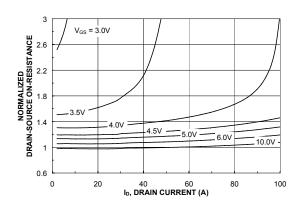


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

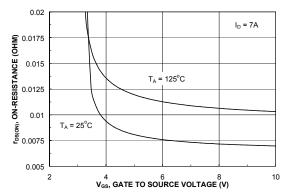


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

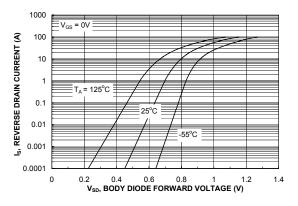


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

# **Typical Characteristics**

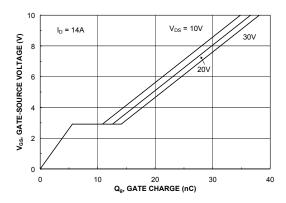


Figure 7. Gate Charge Characteristics

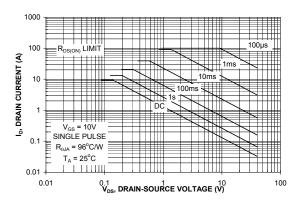


Figure 9. Maximum Safe Operating Area

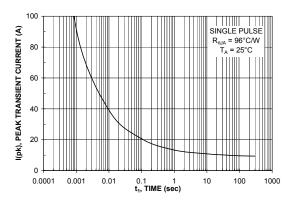


Figure 11. Single Pulse Maximum Peak Current

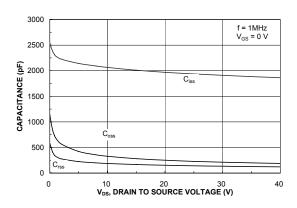


Figure 8. Capacitance Characteristics

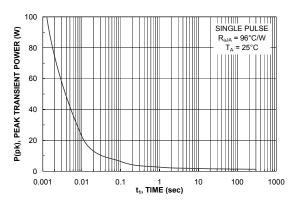


Figure 10. Single Pulse Maximum Power Dissipation

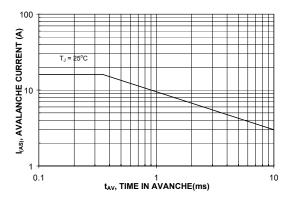


Figure 12. Unclamped Inductive Switching Capability



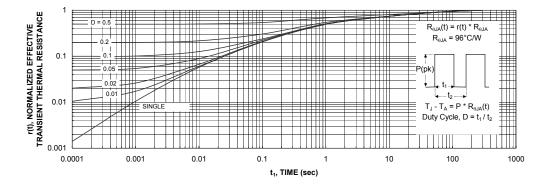


Figure 13. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.





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